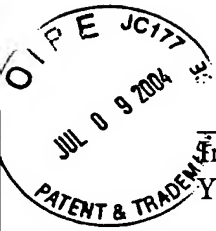


Docket No.: H6808.0040/P040
(PATENT)



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Yoshihiro Kimura et al.

Application No.: 10/779,749

Confirmation No.: 2045

Filed: February 18, 2004

Art Unit: Not Yet Assigned

For: METHOD OF DETERMINING THE
CONCAVITY AND CONVEXITY ON
SAMPLE SURFACE, AND CHARGED
PARTICLE BEAM APPARATUS

Examiner: Not Yet Assigned

CLAIM FOR PRIORITY AND SUBMISSION OF DOCUMENTS

U.S. Patent and Trademark Office
220 20th Street S.
Customer Window
Crystal Plaza Two, Lobby, Room 1B03
Arlington, VA 22202

Dear Sir:

Applicant hereby claims priority under 35 U.S.C. 119 based on the following
prior foreign application filed in the following foreign country on the date indicated:

<u>Country</u>	<u>Application No.</u>	<u>Date</u>
Japan	2003-040494	February 19, 2003

Application No.: 10/779,749

Docket No.: H6808.0040/P040

In support of this claim, a certified copy of the said original foreign application is filed herewith.

Dated: July 8, 2004

Respectfully submitted,

By

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(Translation)

JAPAN PATENT OFFICE

This is to certify that the annexed is a true copy of
the following application as filed with this Office.

Date of Application: February 19, 2004

Application Number: Japanese Patent Application
No. 2003-040494

Applicant(s): Hitachi High-Technologies Corporation

April 27, 2004

Commissioner,
Japan Patent Office

Yasuo Imai (seal)

Certificate No. 2004-3036312